

PATENT ABSTRACTS OF JAPAN

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(54) SOLID-STATE IMAGE PICKUP DEVICE

(57)Abstract:

PROBLEM TO BE SOLVED: To solve a problem of a conventional solid-state image pickup device whose pixel is configured with one photodiode, 4 transistors (TRs) and one capacitor that cannot have utilized only either of a field shutter function and a kTC (k is Boltzman's constant, T is absolute temperature and C is a capacitance) noise cancel function. SOLUTION: After resetting a capacitor Ce by a TR M1a, charge transfer TR M5 is conductive to transfer charges obtained by photoelectric conversion at a photo diode PD to the capacitor Ce where the charges are stored. Then each TR M5 is turned off simultaneously for all the pixels and TRs M1M3 of pixels on the same row are conductive to provide a prescribed level to a CDS (correlation dual sampling) circuit 5. Succeedingly, a TR M6 is conductive and the TR M3 is turned on to output a signal corresponding to the charges by a field shutter function stored in the capacitor Ce to the CDS circuit 5. Thus the CDS circuit transfer can cancel kTC noise.

CLAIMS

[Claim(s)]

[Claim 1] A photo-diode and a converter which transforms into an electrical change an electric charge acquired by said photo-diode carrying out photoelectric conversion. A pixel provided with a transistor for reset for resetting

said converter and an output means which outputs potential of said converter to the exterior. Multiple arrays are carried out to two-dimensional matrix form or one-dimensional line form and two in a state of only background noise where a signal level and a signal level from said pixel have not ridden are sampled. In a solid state camera provided with a noise canceller from which a noise is removed by taking the difference, a capacitor for accumulating an electric charge between said photo-diode and said converter into said pixel temporarily is formed. Between said capacitor and said photo-diode, the 1st transistor for charge transfer after providing the 2nd transistor for charge transfer between said capacitor and said converter respectively, outputting potential of only background noise on which a signal has not ridden by said output means after reset of said converter with said transistor for reset and saving at said noise canceller. Carry out photoelectric conversion with said photo-diode and an electric charge which was transmitted to all the pixel coincidence and accumulated in said capacitor through said 1st transistor for charge transfer at it is transmitted to said converter through said 2nd transistor for charge transfer. The new potential produced in this converter as a result is outputted to said noise canceller by said output means. A solid state camera taking difference with potential of only said background noise beforehand saved in this noise canceller and having a control means which takes out the difference as a true signal.

[Claim 2] A photo-diode and a converter which transforms into an electrical change an electric charge acquired by said photo-diode carrying out photoelectric conversion. A pixel provided with a transistor for reset for resetting said converter and an output means which outputs potential of said converter to the exterior. Multiple arrays are carried out to two-dimensional matrix form or one-dimensional line form and two in a state of only background noise where a signal level and a signal level from said pixel have not ridden are sampled. In a solid state camera provided with a noise canceller from which a noise is removed by taking the difference, the 1st transistor for charge transfer connected to said photo-diode into said pixel. It is approached and provided between the 2nd transistor for charge transfer connected to said converter and the said 1st and 2nd transistors for charge transfer. After outputting potential of only background noise on which a signal has not ridden after providing a MOS gate which accumulates an electric charge from said photo-diode

directly under it and resetting said converter with said transistor for reset by said output means and saving at said noise canceller Carry out photoelectric conversion with said photo-diode and an electric charge which was transmitted directly under said MOS gate and accumulated in all the pixel coincidence through said 1st transistor for charge transfer is transmitted to said converter through said 2nd transistor for charge transfer The new potential produced in this converter as a result is outputted to said noise canceller by said output means A solid state camera taking difference with potential of only said background noise beforehand saved in this noise canceller and having a control means which takes out the difference as a true signal.

[Claim 3] The solid state camera according to claim 1 or 2 connecting the 2nd transistor for reset that is switched to a node of said photo-diode and said 1st transistor for charge transfer to arbitrary timing and resets said photo-diode at the time of one. [Claim 4] A photo-diode and the 1st transistor for reset connected to said photo-diode A converter which transforms into an electrical change an electric charge acquired by said photo-diode carrying out photoelectric conversion The 2nd transistor for reset for resetting said converter The multiple arrays of the pixel provided with an output means which outputs potential of said converter to the exterior are carried out to two-dimensional matrix form or one-dimensional line form Two in a state of only background noise where a signal level and a signal level from said pixel have not ridden are sampled The 1st transistor for charge transfer that is the solid state camera provided with a noise canceller from which a noise is removed by taking the difference and was connected to said photo-diode and the 1st transistor for reset into said pixel It is approached and provided between the 2nd transistor for charge transfer connected to said converter and the said 1st and 2nd transistors for charge transfers said 1st transistor for reset being set to OFF and after providing a MOS gate which accumulates an electric charge from said photo-diode directly under it and resetting said photo-diode with said 1st transistor for reset Said 1st transistor for charge transfer is considered as one in the state where the 1st voltage for setting potential [directly under] of said MOS gate as a middle level at the time of the maximum and the minimum is impressed to said MOS gate Since an electric charge by which photoelectric conversion was carried out is transmitted directly under said MOS gate and stored up with the 1st

shutter time and said photo-diode said 1st transistor for charge transfer is made off After resetting said photo-diode with said 1st transistor for reset again Said 1st transistor for charge transfer is considered as one in the state where the 2nd voltage for making said 1st transistor for reset off and setting potential [directly under] of said MOS gate as a larger level than said 1st voltage is impressed to said MOS gate A solid state camera having a control means which makes off said 1st transistor for charge transfer since an electric charge by which photoelectric conversion was carried out is transmitted directly under said MOS gate and stored up with the 2nd shutter time shorter than said 1st shutter time and said photo-diode.

DETAILED DESCRIPTION

[Detailed Description of the Invention]

[0001]

[Field of the Invention] This invention relates to the CMOS image sensor which was applied to the solid state camera especially had a store-and-forward part in the pixel.

[0002]

[Description of the Prior Art] It roughly divides into the conventional solid state camera and there are two a CCD system and a CMOS sensor system in it. The difference among both is in the place referred to as how to give the information on the electric charge of the photo-diode instead of the photo-diode which changes light into an electric charge out of each photo detector.

[0003] A CCD system transmits directly the electric charge generated in the photo-diode to the exterior by a charge coupled device (CCD: charge coupled device). On the other hand a CMOS sensor system is outputted to the element exterior through the amplifier in which the information on the potential by the electric charge generated in the photo-diode was provided corresponding to each photo-diode. Since the pixel structure of this CMOS sensor system can be created in the almost same process as the usual CMOS-LSI process the line for CMOS-LSI can be used as it is and there is a merit that an area sensor and other CMOS circuits can be intermingled.

[0004] On the other hand there is a problem that fixed pattern noise is loud compared with a CCD system in a CMOS sensor system. Fixed pattern noise mainly originates in the variation in the threshold voltage of the transistor for amplifier.

[0005] Drawing 7 shows the block diagram of an example of the conventional solid state camera. This conventional solid state camera shows the most common CMOS image sensor. Pixel 2_{11} - 2_{33} etc. are arranged at two-dimensional matrix form and with the vertical shift register 1 among these pixel 2_{11} - 2_{33} . Operation of two or more (arranged horizontally) pixels of each line is controlled for every line (it usually goes to a lower line from the upper line) and the signal from each pixel 2_{11} - 2_{33} is inputted into load and the noise canceller 3 and after noise cancellation operation is carried out one by one with the horizontal shift register 4 and the signal of each sequence is outputted as an imaging signal. [the transistor T1 - T3]

Usually processing follows processing to a left sequence from a right sequence. A row and column can also be arranged conversely. It is also possible to arrange a pixel not to two-dimensional matrix form but to the one-dimensional line form of one row.

[0006] The noise canceller called a CDS circuit with a pixel is attached to the solid state camera of this former i.e. the conventional CMOS image sensor. There is this in order to remove background noise (mainly variation of the threshold voltage of the transistor for amplifier of a pixel) when the signal is not contained from the output signal of a pixel.

[0007] Drawing 8 shows the representative circuit schematic of an example for 1 pixel of the conventional solid state camera called a CMOS image sensor. Identical codes are given to drawing 7 and an identical configuration portion among the figure. The one pixel 2a consists of one photo-diode PD, the transistors M1 for reset by which the source was connected to the N type layer of photo-diode PD, the transistors M2 for amplification by which the gate was connected to the N type layer of photo-diode PD and the transistors M3 for transmission in drawing 8. The transistor M1, M2 and M3 are MOS type field effect transistors (FET) and are usually FET of an n channel.

[0008] The source of the transistor M2 is connected to the double correlation sampling (CDS) circuit 5 and the load 6 through the transistor M3 with a switch function. The transistor M3 operates as a source follower circuit. CDS circuit 5 comprises the two capacitors C1 and C2 and the two switches S1 and S2.

The non-grounded side terminal of the capacitor C1 is connected to the source of the transistor M3 via the switch S1 and the capacitor C2 in series. The switch S1 side

terminal C2a of the capacitor C2 is connected to the reference voltage Vref via the switch S2 and the switch S1 side terminal C1b of the capacitor C1 is connected to the signal output line via the switch S3.

[0009] CDS circuit 5 and the load 6 are the circuitry portions for one row of pixels the load of drawing 7 and among the noise cancellers 3. CDS circuit 5 samples two in the state of only background noise where the signal level and signal level from a pixel have not ridden and carries out the role of the noise canceller from which a noise is removed by taking the difference. A current regulator circuit is usually used for the load 6.

[0010] Next operation of equipment is explained conventionally [this]. Now the pixel 2a in drawing 8 presupposes that it is a pixel of a sequence with the line of somewhere middle which are not the top line and a lowermost row. First the transistor M1 is made off [one and the transistor M3] and makes a reset state the terminal T1 by the side of the N type layer of photo-diode PD. Potential of the terminal T1 at this time is made into reset voltage ($V_{dd}-V_{thrst}$). Here V_{dd} is power supply voltage and V_{thrst} is the threshold voltage of the transistor M1. At this reset state since the transistor M3 is off there is no output from this pixel 2a in a column signal line.

[0011] Next the light from a photographic subject is entered into photo-diode PD and photoelectric conversion is made to perform where the transistor M1 is made off. Thereby the electric charge according to incident light quantity is accumulated in photo-diode PD. The capacity C_{px1} in the terminal T1 serves as the capacity C_{pd} of photo-diode PD and gate capacitance C_{amp} of the transistor M2 from the diffusion capacitance C_{rst} of the transistor M1 and the stray capacitance C_f of wiring. If the amount Q of net charge occurs in photo-diode PD the electrical change of only $\Delta V = Q/C_{px1}$ will occur in this terminal T1. On the other hand CDS circuit 5 is processing the output signal of the pixel of other lines in the meantime.

[0012] Processing of the output signal of the pixel (not shown) of the continued line of the pixel 2a which CDS circuit 5 is observing is ended and if a processing result is outputted through the switch S3 closed with the horizontal shift register 4 CDS circuit 5 will start processing of the pixel 2a currently observed. CDS circuit 5 performs its reset action first.

[0013] That is the switch S1 and S2 are closed and potential of the terminal C2a and the terminal C1b is set to reference-potentials Vref. If high-level voltage is

impressed to the gate of the transistor M3 in this state and M3 is made one. The potential ($V_{dd}-V_{thrst}+V$) of the terminal T1 of photo-diode PD is amplified with the transistor M2 and also the potential which lets the drain of the transistor M3 and a source pass ($V_{dd}-V_{thrst}-V_{thamp}+V$) is outputted to a column signal line (that is terminal C2b). Thereby the potential difference of ($V_{dd}-V_{thrst}-V_{thamp}+V-V_{ref}$) is built over the capacitor C2. Here V_{thamp} is the threshold voltage of the transistor M2.

[0014] Then the switch S2 is opened, reset voltage is impressed to the gate of the transistor M1 and M1 is considered as one. Then since the potential of the terminal T1 of photo-diode PD serves as ($V_{dd}-V_{thrst}$) the potential of terminal C2b serves as ($V_{dd}-V_{thrst}-V_{thamp}$). It means that as for terminal C2b potential has changed by this only in ($V_{dd}-V_{thrst}-V_{thamp}$)-($V_{dd}-V_{thrst}-V_{thamp}+V$) = -V. This is equal to a part for the voltage change by the side of the terminal T1 of photo-diode PD. Therefore only the amount of [by the photoelectric conversion of photo-diode PD] voltage change is able to take out purely by a series of above-mentioned operations.

[0015] As a result as for the potential of the terminal C2a (= terminal C1b) only the proportional component with which the capacitor C1 and C2 were connected in series by voltage change part V changes. That is $V_{ref}-\{V-C1/(C1+C2)\}$ (1). It becomes. Then the switch S1 is opened and it supposes that it is off and a processing result is held to the capacitor C1 and it stands by to it. Then the transistor M3 is come by off and that of the output from the pixel 2a is lost. Then the processing result of (1) type which the switch S3 was closed to a certain timing and was held with the horizontal shift register 4 of drawing 7 at the capacitor C1 is outputted as a pixel signal. Then the switch S3 opens. It is supposed that it is off and it returns to the first reset state. The operation same also about each pixel as the above is performed. [0016] However in the CMOS image sensor of drawing 8 shutter functions pose a problem. That is in CCD since carriers are moved from a photo-diode to a transfer region all at once at a certain moment the picture information obtained from CCD has simultaneity in all the pixels in 1 screen and CCD has shutter functions intrinsically.

[0017] On the other hand since the CMOS image sensor of drawing 8 is read in order for every line the picture created using this information shows time to be different for every line. Therefore it will be the perverted picture if Still Picture Sub-Division is taken out. The shutter of

such picture shifted in time is called rolling shutter in many cases.

[0018]The shutter which makes Still Picture Sub-Division to which it was equal in time on the other hand is called field shutter in many cases. One method of giving a field shutter function with the conventional CMOS image sensor of the composition of drawing 8 only with the function of a rolling shutter is providing a mechanical shutter. That is a mechanical shutter is provided in addition to an element and only a certain specific time should open a shutter. However in this method cost becomes high and photography of an animation is difficult.

[0019]In order to attach a field shutter function it is indispensable to have a switch which takes out a certain instantaneous picture information simultaneously by all the pixels and an accumulating part which stores it temporarily. Then the transistor M4 and the capacity Ce are usually applied to a picture element part like drawing 9 and it realizes. Identical codes are given to drawing 8 and an identical configuration portion among the figure and the explanation is omitted. In drawing 9 with MOS transistor M4 by which the drain and the source were further connected to the pixel 2a of drawing 8 between the N type layer of photo-diode PD and the terminal T1 one end is connected to the terminal T1 and pixel 2b has the feature in the point of having added further the capacitor Ce for adjustment by which the other end was grounded. The transistor M4 takes charge of shutter functions and the capacitor Ce takes charge of an accumulating function. The gate capacitance of the transistor M2 etc. may be enough as the capacitor Ce and it does not need to form the capacitor Ce in particular in that case. The operation at the time of having such composition is shown below.

[0020]Pixel 2b presupposes that it is a pixel of a sequence with the line of somewhere middle which are not the top line of a picture element part and a lowermost row. In explaining the cycle of operation of a pixel it carries out [that the output of the information last now just finished and]. The transistor M1, M3 and M4 are come by off in this state. The potential of the terminal T1 at this time is ($V_{dd} - V_{thrst}$). Here V_{dd} is power supply voltage and V_{thrst} is the threshold voltage of the transistor M1. Since the terminal T1 was not connected anywhere but has floated electrically at this time it is still reset potential. Since the transistor M3 is off there is no output from pixel 2b in a column signal line. Photoelectric conversion is performed in photo-diode PD which the transistor M4 also serves as

OFF therefore is electrically separated from the terminal T1 on the other hand. Performing photoelectric conversion in this way it is waiting for pixel 2b until the information on the pixel of all the lines below itself is read. [0021] In this way one [the transistors M4 of all the pixels] all at once if the signal of all the pixels is read and predetermined time passes after a photoelectric conversion start. Then the electric charge accumulated in the N type layer side of photo-diode PD is simultaneously transmitted to the terminal T1 by all the pixels. As a result the electric charge of photo-diode PD is lost and PD is reset. After transmission is completed the transistor M4 is come by off and photo-diode PD starts photoelectric conversion again.

[0022] The capacity C_{px1} of the terminal T1 consists of the capacitor C_{gate} capacitance C_{amp} of the transistor M2 and the diffusion capacitance C_{rst} of the transistor M1 and the stray capacitance C_f of wiring. Therefore if the transmitted amount of net charge sets to Q the electrical change of only $V = Q/C_{px1}$ will happen to the terminal T1. Since the carrier transmitted is an electron the electric charge Q is a negative value therefore V is also a negative value. Since the potential of the terminal T1 was $(V_{dd} - V_{thrst})$ before charge transfer after charge transfer is set to $(V_{dd} - V_{thrst} + V)$.

[0023] After transmission of an electric charge is completed by all the pixels CDS circuit 5 performs signal processing for every line. While processing other lines pixel 2b currently observed stands by holding an electric charge to the capacitor C_e connected to the terminal T1. And CDS circuit 5 starts processing of pixel 2b currently observed. First its reset action is performed. That is as mentioned above the switch S1 and S2 are closed and potential of the terminal C2a and the terminal C1b is set to reference-potentials V_{ref} . At this time the switch S3 is opened and is come by off. If high-level voltage is impressed to the gate of the transistor M3 in this state and M3 is made on the potential of $(V_{dd} - V_{thrst} - V_{thamp} + V)$ will be outputted to a column signal line (getting it blocked terminal C2b). Thereby the potential difference of $(V_{dd} - V_{thrst} - V_{thamp} + V - V_{ref})$ is built over the capacitor C2.

[0024] Then since it is not anywhere connected with the terminal C2a (= terminal C1b) if the switch S2 is opened and it turns OFF will be floated electrically. Here the transistor M1 is once made on it turns OFF after predetermined time and the terminal T1 is reset. Then since the potential of the terminal T1 serves as $(V_{dd} - V_{thrst})$ the

potential of terminal C2b serves as $(V_{dd}-V_{thrst}-V_{thamp})$. Therefore it means that as for the potential of terminal C2b only $(V_{dd}-V_{thrst}-V_{thamp})-(V_{dd}-V_{thrst}-V_{thamp}+V) = -V$ had changed. This is an ingredient proportional to the charge quantity Q generated in photo-diode PD. Therefore only the amount of [by the photoelectric conversion of photo-diode PD] signal is able to take out purely by a series of above-mentioned operations. [0025] As a result as for the potential of the terminal C2a (= terminal C1b) only the proportional component with which the capacitor C1 and C2 were connected in series by change part- V changes. That is only the same value as the aforementioned (1) formula changes. Then the switch S1 is opened and it supposes that it is off and a processing result is held to the capacitor C1 and it stands by to it. Then the transistor M3 is come by off and that of the output from pixel 2b is lost. Then the processing result of (1) type which the switch S3 was closed to a certain timing and was held with the horizontal shift register 4 of drawing 7 at the capacitor C1 is outputted as a pixel signal. Then the switch S3 opens it is supposed that it is off and it returns to the first state. In this way one cycle of a series of processings is completed and the same operation as the following is repeated. [0026]

[Problem to be solved by the invention] However a serious problem is among the CMOS image sensors with a field shutter function which are the conventional solid state cameras shown in above-mentioned drawing 9. That is in the conventional equipment of drawing 9 after transmitting the electric charge of photo-diode PD to the terminal T1 reset beforehand generating potential with it and outputting it out of a pixel it is reset again and used as the level of the standard for cancellation. That is the reset action of different timing is used in the time of outputting a signal and the time of outputting a background. Thus when the voltage by the reset action of another timing is compared there is a problem that a kTC noise is not removed. [0027] This kTC noise is the noise resulting from electronic thermal agitation. For example making potential of a certain capacity C into a certain potential V is giving the electron of the electric charge q to the capacity C only several predetermined piece (or it removes) like drawing 10. Several of the n can be expressed like a following formula.

[0028]

$$n = V / (C - q) \quad (2)$$

If switch S4 is opened after connecting the capacity C with

the power supply of the voltage V via the resistance R and switch S_4 closing switch S_4 and sufficiently long time's passing as shown in drawing 10 as concrete operation an above-mentioned number of electrons are stored in the capacity C and both ends have the voltage V .

[0029] However since the electron is carrying out thermal agitation at random actually while having closed switch S_4 the number of the electron number in the capacity C of electronic increases more than n at a certain time and there is variation in time as smaller than n when another. For this reason when switch S_4 is opened and it turns Off it is more than n in be alike by chance or there will be few electron numbers which remained in the capacity C then. This variation serves as noise called a kTC noise and appears. kTC -- k : -- they are a Boltzmann constant T : absolute temperature and C : capacity -- the noise level V_i -- rms -- $V_i = \sqrt{kTC}$ (3)

It is expressed. (3) as shown in a formula it is the feature to depend for this noise level V_i only on temperature and capacity.

[0030] Therefore in the terminal T_1 of a CMOS image sensor of drawing 9 if a thing of timing of two different reset is compared the noise level V_{i1} and V_{i2} different respectively can remain and cannot cancel. There is no correlation in such noise level V_{i1} and V_{i2} when comparing a thing which is not such correlated a kTC noise is root doubled and it is $V_i = \sqrt{2 kTC}$ (4).

It becomes.

[0031] As shown in the above-mentioned (3) types and (4) types a kTC noise becomes so large that capacity is small. For this reason with composition of drawing 8 and drawing 9 if a pixel is miniaturized it will become impossible to take large C_{pxl} gradually and a kTC noise will become large.

[0032] Here a kTC noise is estimated quantitatively. For example suppose that the capacity C_{pxl} of the terminal T_1 was set to 8fF. A numerical value of these 8fF is a numerical value which is tinged with a touch of reality when pixel size becomes below a 5-micrometer mouth. At this time kTC noise part V_i is set to about 1 mV at a room temperature of $T = 300$ degrees K. If a noise considers it only as a kTC noise by 2V in the peak magnitude of a signal a S/N ratio of the above-mentioned CMOS image sensor with a field shutter function will be set to 46 dB. Since it is said that a S/N ratio of a CCD system is not less than 60 dB it is only a kTC noise and it turns out that performance is considerably inferior as compared with a CCD system.

[0033]In CMOS image sensor composition of the easiest structure of aforementioned drawing 8 since the capacity Cpd of photo-diode PD is quite large in capacity of the terminal T1a problem is smaller than a case of composition of drawing 9. However it is impossible to remove a kTC noise with composition of drawing 8.

[0034]Since there are more transistors than composition of drawing 8 when it miniaturizes it becomes impossible on the other hand to cleave big capacity gradually for the terminal T1 in the conventional CMOS image sensor of composition of drawing 9. Therefore the composition of drawing 9 of the necessity of controlling a kTC noise is higher. In composition of this drawing 9 if not a field shutter but rolling shutter operation is performed a kTC noise is removable.

[0035]Rolling shutter operation is performed as follows with the composition of drawing 9. First the transistor M4 and M3 presuppose that it is off. At this time there is no output from this pixel 2b in column signal line C2b. At this time light enters into photo-diode PD of pixel 2b photoelectric conversion is performed and an electric charge is accumulated in photo-diode PD. CDS circuit 5 is processing the signal of the element of other lines.

[0036]Next processing of the line currently observed starts. And the terminal T1 is reset by ($V_{dd}-V_{thrst}$). [the transistor M1] Then the transistor M1 is turned off. Then the transistor M3 is considered as one. At this time the transistor M4 is still OFF. Thereby a signal ($V_{dd}-V_{thrst}-V_{thamp}$) when the terminal T1 is reset is outputted to a column signal line. In CDS circuit 5 the switches S1 and S2 are closed and the potential difference of ($V_{dd}-V_{thrst}-V_{thamp}-V_{ref}$) is saved to the capacitor C2.

[0037]Next the switch S2 is opened and suppose that it is off. Then the transistor M4 is considered as one. Thereby the electric charge of photo-diode PD flows into the terminal T1 through the drain of the transistor M4 and a source. The capacity Cpx1 of the terminal T1 serves as the capacitor Cc and gate capacitance Camp of the transistor M2 from the diffusion capacitance Crst of the transistor M1 and the stray capacitance Cf of wiring. If the amount of net charge of photo-diode PD is set to Q the electrical change of only $\Delta V = Q/C_{px1}$ will occur in this terminal T1. The potential of this terminal T1 is amplified with the transistor M2 lets the transistor M3 which is one pass and is outputted to a column signal line as ($V_{dd}-V_{thrst}-V_{thamp}+\Delta V$).

[0038]Thereby since change of the potential of terminal C2b is set to ($V_{dd}-V_{thrst}-V_{thamp}+\Delta V$) - ($V_{dd}-V_{thrst}-$

$V_{thamp} = +V_{potential} V_{ref} + \{ *V - C_1 / (C_1 + C_2) \}$ proportional to it appears in the terminal C1b. This potential is outputted to the horizontal shift register 4. Then the transistor M3 is made off and it is considered as the first reset state.

[0039] Since reset will be performed only once but background noise will be removed from a signal in the same reset action if it does in this way a kTC noise can also be removed. Since there is such a characteristic composition like drawing 9 is used in little rolling shutter operation of noise rather than for field shutter operation in many cases.

[0040] Thus since the accumulating function part and the electric charge voltage converting function part were independently the photoelectrical load conversion function part of photo-diode PD and temporarily [electric charge] respectively with neither of the conventional solid state cameras drawing 8 nor drawing 9 In the solid state camera of the pixel configuration set to one photo-diode PD like drawing 8 from the three transistors M1-M3. The three above-mentioned function parts are united while there is the feature of being constitutionally very simple a field shutter function and a kTC noise cancel function cannot be realized as the result but there is a problem that high-definition Still Picture Sub-Division equal in time cannot be obtained. [0041] In the solid state camera of the pixel configuration which consists of one photo-diode PD shown in drawing 9 the four transistors M1-M4 and the one capacitor Ce. While Still Picture Sub-Division equal in time with a field shutter function can be obtained there is a problem that only one of a field shutter function and the kTC noise cancel functions can be used.

[0042] This invention was made in view of the above point and an object of this invention is to provide the solid state camera which can realize simultaneously a field shutter function and a kTC noise cancel function.

[0043] Other purposes of this invention are to make area of a photo-diode small and to provide the solid state camera of composition advantageous to a miniaturization.

[0044]

[Means for solving problem] The converter which transforms into an electrical change the electric charge acquired by a photo-diode and a photo-diode carrying out photoelectric conversion in order that this invention may attain the above-mentioned purpose A pixel provided with the transistor for reset for resetting a converter and the output means which outputs the potential of a converter to the

exteriorMultiple arrays are carried out to two-dimensional matrix form or one-dimensional line form and two in the state of only background noise where the signal level and signal level from a pixel have not ridden are sampled in the solid state camera provided with the noise canceller from which a noise is removed by taking the differenceThe capacitor for accumulating an electric charge between a photo-diode and a converter into a pixel temporarily is formedBetween a capacitor and a photo-diode the 1st transistor for charge transferAfter providing the 2nd transistor for charge transfer between a capacitor and a converter respectively outputting the potential of only the background noise on which a signal has not ridden by an output means after reset of a converter with the transistor for reset and saving at a noise cancellerCarry out photoelectric conversion with a photo-diode and the electric charge which was transmitted to all the pixel coincidence and accumulated in the capacitor through the 1st transistor for charge transfer at it is transmitted to a converter through the 2nd transistor for charge transferThe new potential produced in the converter as a result is outputted to a noise canceller by an output means difference with the potential of only the background noise beforehand saved in the noise canceller is taken and it has composition which has a control means which takes out the difference as a true signal.

[0045]After accumulating in a capacitor the electric charge acquired by carrying out photoelectric conversion simultaneously with the photo-diode of all the pixels in this inventionAfter making the potential of only the background noise on which it faces outputting to the exterior through an output means the transistor for reset and an output means are operated and a signal has not ridden send out and save to a noise cancellerBy outputting the signal corresponding to the electric charge accumulated in the capacitor to a noise canceller through an output means from a converter only the signal component proportional to the electric charge produced by the photoelectric conversion of the photo-diode in the noise canceller can be taken out.

[0046]In order to attain the above-mentioned purpose this inventionThe 1st transistor for charge transfer connected to the photo-diode into the pixelIt is approached and provided between the 2nd transistor for charge transfer connected to the converter and the 1st and 2nd transistors for charge transferThe MOS gate which accumulates the electric charge from a photo-diode is provided directly

under itAfter outputting the potential of only the background noise on which a signal has not ridden after resetting a converter with the transistor for reset by an output means and saving at a noise cancellerCarry out photoelectric conversion with a photo-diodeand the electric charge which was transmitted directly under the MOS gate and accumulated in all the pixel coincidence through the 1st transistor for charge transfer is transmitted to a converter through the 2nd transistor for charge transferThe new potential produced in the converter as a result is outputted to a noise canceller by an output meansdifference with the potential of only the background noise beforehand saved in the noise canceller is takenand it has composition which has a control means which takes out the difference as a true signal.

[0047]After accumulating the electric charge acquired by carrying out photoelectric conversion simultaneously with the photo-diode of all the pixels in this invention directly under a MOS gateAfter outputting the potential of only the background noise on which it faces outputting to the exterior through an output meansthe transistor for reset and an output means are operatedand a signal has not ridden by an output means and making it save at a noise cancellerBy outputting the signal corresponding to the electric charge accumulated directly under the MOS gate to a noise canceller through an output means from a converteronly the signal component proportional to the electric charge produced by the photoelectric conversion of the photo-diode in the noise canceller can be taken out.

[0048]Hereit is switched to the node of a photo-diode and the 1st transistor for charge transfer to arbitrary timingand reset of a photo-diode can be performed to arbitrary timing by connecting the 2nd transistor for reset that resets a photo-diode at the time of one.

[0049]In order to attain the above-mentioned purposethis inventionA photo-diode and the 1st transistor for reset connected to the photo-diodeThe converter which transforms into an electrical change the electric charge acquired by a photo-diode carrying out photoelectric conversionA pixel provided with the 2nd transistor for reset for resetting a converter and the output means which outputs the potential of a converter to the exteriorMultiple arrays are carried out to two-dimensional matrix form or one-dimensional line formand two in the state of only background noise where the signal level and signal level from a pixel have not ridden are sampledThe 1st transistor for charge transfer that is the solid state camera provided with the noise canceller

from which a noise is removed by taking the difference and was connected to a photo-diode and the 1st transistor for reset into the pixel. The 2nd transistor for charge transfer by which the end was connected to the output means and the 2nd transistor for reset connected to the 2nd transistor for charge transfer and output means respectively. It is approached and provided between the 1st and 2nd transistors for charge transfer and the MOS gate which accumulates the electric charge from a photo-diode directly under it is established in each of each pixel. After resetting a photo-diode with the 1st transistor for reset, in the state where the 1st voltage for making the 1st transistor for reset off and setting the potential [directly under] of a MOS gate as the middle level at the time of the maximum and the minimum is impressed to a MOS gate, consider the 1st transistor for charge transfer as one and the 1st shutter time. Since the electric charge by which photoelectric conversion was carried out is transmitted directly under a MOS gate and stored up with a photo-diode, the 1st transistor for charge transfer is made off. After resetting a photo-diode with the 1st transistor for reset again, the 1st transistor for charge transfer is considered as one in the state where the 2nd voltage for making the 1st transistor for reset off and setting the potential [directly under] of a MOS gate as a larger level than the 1st voltage is impressed to a MOS gate. Since the electric charge by which photoelectric conversion was carried out is transmitted directly under a MOS gate and stored up with the 2nd shutter time shorter than the 1st shutter time and a photo-diode, it has composition which has a control means which makes the 1st transistor for charge transfer off. [0050] In this invention, the electric charge which carried out photoelectric conversion to the electric charge which carried out photoelectric conversion with the photo-diode by the 1st shutter time of the longer one with the photo-diode by the 2nd shutter time of the shorter one can be added directly under a MOS gate.

[0051]

[Mode for carrying out the invention] Next, an embodiment of the invention is described with Drawings. Drawing 1 shows the representative circuit schematic of one pixel circuit of a 1st embodiment of the solid state camera which becomes this invention. Identical codes are given to drawing 8, drawing 9 and an identical configuration portion among the figure. According to a 1st embodiment shown in drawing 1 compared with pixel 2b of drawing 9a, a MOS type field effect transistor (FET) and one capacitor are added respectively and

the pixel 2c is made one photo-diode five transistors and 2 capacitor composition. Namely as for the pixel 2c the N type layer side of photo-diode PD is connected to the source of the transistor M1 for reset and the gate of the transistor M2 in the node (terminal) T1 via the drain of the transistor M5a source and the drain of the transistor M6 and the source respectively. [0052] The common node of the transistors M5 and M6 is grounded via the capacitor Cex. The terminal T1 is grounded via the capacitor Ce. The source of the transistor M2 is connected to CDS circuit 5 and the load 6 via the drain of the transistor M3 for an output and the source respectively. The capacitor Cex consists of N⁻ diffusion zones made for example to p substrate face. In particular when the sum total of gate capacitance Camp of the transistor M2 the diffusion capacitance Crst of the transistor M1 and the stray capacitance Cf of wiring is enough as the capacity Cpxl of the terminal T1 it is not necessary to form the capacitor Ce. The capacity Cpxl of the terminal T1 constitutes the converter which transforms into voltage the electric charge mentioned above with the capacitor Ce.

[0053] Next operation of this embodiment is explained. Here the pixel 2c presupposes that it is a pixel of a sequence with the line of somewhere middle which are not the top line of a picture element part and a lowermost row. Switching control of each transistor M1 M3 M5 and M6 is performed based on the signal from the control circuit which is not illustrated. [0054] It begins from the place said [that the output of the last signal of this pixel 2c has just finished as a starting point of motion cycle explanation and]. In this state the transistor M1 and M6 are off and the terminal T1 is in the state where it floated electrically. In the last cycle photo-diode PD carried out photoelectric conversion to the terminal T1 and the transistor M5 and the electric charge transmitted through M6 remain in it as it is. The transistor M3 also serves as OFF and there is no output from this pixel 2c to a column signal line.

[0055] On the other hand the transistor M5 also serves as OFF and photo-diode PD performs photoelectric conversion in the state where it dissociated from others electrically and is accumulating the electric charge. The electric charge which suited the capacitor Cex is transmitted to the terminal T1 through the transistor M6 and is in the state where there is no electric charge in the capacitor Cex. [0056] In such a state the pixel 2c is waiting for CDS circuit 5 to end the processing which is a pixel of other

lines. The one [the transistors M5 / all the pixels including the pixel 2c] all at once after signal read-out from all the pixels is completed. Then the electric charge Q accumulated in photo-diode PD is simultaneously transmitted to each capacitor Cex through each transistor M5 by all the pixels. As a result the electric charge of photo-diode PD is lost and is reset. It is supposed after the end of charge transfer that the transistor M5 is off again. Photoelectric conversion of photo-diode PD is carried out and it starts accumulation of an electric charge.

[0057] Then the pixel 2c stands by while CDS circuit 5 is carrying out processing which is a pixel of other lines. If processing of the pixel 2c currently observed starts the pixel 2c will perform the reset action of the terminal T1. That is the high-level signal from the control circuit which is not illustrated is impressed to the gate electrode of the transistor M1 and makes M1 on. At this time the transistor M3 and M6 are still OFF. As a result the potential of the terminal T1 serves as $(V_{dd}-V_{thrst})$. Here V_{dd} is power supply voltage and V_{thrst} is the threshold voltage of the transistor M1.

[0058] Then the signal to the gate electrode of the transistor M1 serves as a low level and is made off [M1]. Thereby the terminal T1 returns to the state where it floated electrically and a reset action completes it. Since the kTC noise ingredient V_{ktc} rides on the terminal T1 at this time the potential of the terminal T1 serves as $(V_{dd}-V_{thrst}+V_{ktc})$. Although V_{ktc} was not specified during explanation of conventional technology it decides to be shown in order to show clearly that it is removable by this embodiment. [0059] On the other hand the preparations for carrying out signal processing of the pixel 2c even in CDS circuit 5 are made. That is the switch S1 and S2 are closed and the terminal C2a and C1b are made into the reference potential V_{ref} . Since M3 is considered as one by impressing a high-level signal from the control circuit which is not illustrated to the gate electrode of the transistor M3 in this state the potential of $(V_{dd}-V_{thrst}+V_{ktc}-V_{thamp})$ is outputted to multiple-message-transmission item output line i.e. terminal C2b. Here V_{thamp} is the threshold voltage of the transistor M2 for amplification. As a result the potential difference of $(V_{dd}-V_{thrst}+V_{ktc}-V_{thamp}-V_{ref})$ is built over the capacitor C2.

[0060] Next CDS circuit 5 opens the switch S2 sets it to OFF and changes the terminal C2a (= terminal C1b) into the state where it floated. Here it is considered as one by impressing a signal with the transistor M6 high-level from the control

circuit which is not illustrated to the gate electrode. Then the electric charge Q currently held at the capacitor C_{ex} is transmitted to the terminal $T1$ through the transistor $M6$. The transistor $M6$ after charge transfer completion is made off. As a result an electric charge is lost to the capacitor C_{ex} and it will be in the state where it was reset to it.

[0061] On the other hand for the terminal $T1$ the electrical change by the electric charge Q is generated. Although the capacity C_{px1} of the terminal $T1$ consists of the capacity of the capacitor C_{gate} , capacitance C_{amp} of the transistor $M2$ and the diffusion capacitance C_{rst} of the transistor $M1$ and the stray capacitance C_f of wiring when the electric charge Q enters here the electrical change of $\Delta V = Q/C_{px1}$ occurs. Therefore the potential of the terminal $T1$ is set to $(V_{dd} - V_{thrst} + V_{ktc} + \Delta V)$.

[0062] If an electrical change happens to the terminal $T1$ it will be amplified by the source follower circuit with the transistor $M2$ and also will be told through the transistor $M3$ in an ON state to multiple-message-transmission item output line 1, i.e. terminal $C2b$. Thereby the potential of terminal $C2b$ is set to $(V_{dd} - V_{thrst} + V_{ktc} - V_{thamp} + \Delta V)$. That is the electrical change produced in terminal $C2b$ is $(V_{dd} - V_{thrst} + V_{ktc} - V_{thamp} + \Delta V) - (V_{dd} - V_{thrst} + V_{ktc} - V_{thamp}) = \Delta V$. It is influenced only by the ingredient by the charge quantity Q by the photoelectric conversion of photo-diode PD but there is also no influence of a kTC noise.

[0063] According to the electrical change of this terminal $C2b$ the electrical change of proportionality part $V_{ref} + \{\Delta V - C1/(C1+C2)\}$ with which the capacitor $C1$ and $C2$ were connected in series produces the terminal $C2a$ (= terminal $C1b$) which is in the state which floated electrically. Then the switch $S1$ is opened it supposes that it is off and the processing result which is the above-mentioned electrical change is held to the capacitor $C1$. And it is supposed that the transistor $M3$ is off and the output from the pixel $2c$ is lost. Then the switch $S3$ is considered as one with the horizontal shift register which is not illustrated and the processing result of the pixel $2c$ currently held at the capacitor $C1$ is outputted as a pixel signal through the switch $S3$. Then the switch $S3$ is opened again it is supposed that it is off and one cycle in this pixel $2c$ is completed. In the back the same thing is again repeated from the beginning. [0064] Explanation of operation of the above-mentioned embodiment is an example and is not limited to this. For example what is necessary is to perform reset with the transistor $M1$ of the terminal $T1$ by the

above-mentioned explanation just before outputting the reset potential of the terminal T1 but just to perform it once to [somewhere in] the next signal output operation after it is not limited to this and the last signal output finishes. For example immediately after the last signal output finishes the transistor M1 is made on and it may be made to perform the reset action of the terminal T1 first of all.

[0065] Although reset of the capacitor Cex is performed by transmitting the stored charge of Cex thoroughly by the above-mentioned explanation it cannot transmit if there is too much stored charge and the phenomenon in which an electric charge remains in Cex may arise and it may serve as an afterimage. For this reason before and transmitting an electric charge to the capacitor Cex from photo-diode PD once and it may be made to perform operation which resets the capacitor Cex compulsorily. [the transistor M5] [the transistors M1 and M6]

[0066] thus the background noise out of the signal [according to this embodiment] according to the charge transfer of photo-diode PD in CDS circuit 5 -- it is $(V_{dd} - V_{thrst} - V_{thamp} + V_{ktc})$ -- it being removed and Since voltage change part ΔV proportional to the amount Q of net charge produced by the photoelectric conversion of photo-diode PD can take out to multiple-message-transmission item output line C2b purely the cancel function of a kTC noise is realizable.

[0067] It is also possible only for predetermined time to hold an electric charge to the capacitor Cex. Since the electric charge acquired by carrying out photoelectric conversion of the light which entered simultaneously to the photo-diode of all the pixels containing photo-diode PD in this embodiment is transformed into voltage and he is trying to output its field shutter function can be realized and Still Picture Sub-Division in the same time can be obtained. As mentioned above compared with the former high-definition Still Picture Sub-Division can be picturized. [0068] By the way although the area of the pixel is restricted when the number of transistors is increased rapidly according to it the area of the photo-diode will decrease to it. Then the charge quantity Q generated with a photo-diode will decrease and the sensitivity to a luminosity will become low as an image sensor. However in the composition of this embodiment the fall of the area of the above-mentioned photo-diode does not become disadvantageous but works advantageously rather.

[0069] That is in this embodiment since it can be expressed

with $V = Q/C_{pxl}$ change V of the potential of the terminal T1 can make an electric charge transfer factor high if C_{pxl} is made small. Therefore sensitivity will become fixed if only the rate to which the area of the photo-diode became small makes C_{pxl} small. The more it makes capacity C_{pxl} small since sensitivity becomes high the more it becomes advantageous.

[0070] On the other hand since a kTC noise will become large in the conventional composition shown in drawing 8 or drawing 9 if capacity C_{pxl} is made small as shown in (3) types and (4) types in the former C_{pxl} cannot be made small. However since field shutter operation and removal of a kTC noise will be simultaneously attained if it has composition of this embodiment C_{pxl} can be made small and area of a photo-diode can also be made small. Therefore it is composition advantageous to a miniaturization.

[0071] Next a 2nd embodiment of this invention is described. The feature of this invention is in the composition which makes the photo-diode which performs photoelectric conversion the site which holds temporarily the carrier which the photo-diode generated and the site which transforms the electric charge of a carrier into voltage become independent respectively. Here not a capacitor but an option is possible for the composition of the site which holds a carrier temporarily. Then this 2nd embodiment holds a carrier by a MOS gate.

[0072] Drawing 2 shows the representative circuit schematic for 1 pixel of a 2nd embodiment of the solid state camera which becomes this invention. Identical codes are given to drawing 1 and an identical configuration portion among the figure. According to this 2nd embodiment instead of the capacitor Cex of drawing 1 as shown in drawing 2 the transistors M5 and M6 are approached the gate Mcd of MOS is arranged and the feature is at the point using 2 d of pixels of the structure where an electric charge can be held under MOS gate Mcd. The potential at this time and the situation of movement of an electric charge are shown in drawing 3. Like drawing 1 since Ce is the additional capacities for adjustment omitting is a function. [0073] Next operation of this embodiment is explained with drawing 2 and drawing 3. 2 d of pixels presuppose that it is a pixel of a sequence with the line of somewhere middle which are not the top line of a solid state camera and a lowermost row. It begins from the place said [that the output of the last signal of 2d of this pixel has just finished as a starting point of motion cycle explanation and]. [0074] In this state the transistor M1 and M6 are off and the terminal T1 is in the

state where it floated electrically. In the last cycle photo-diode PD carried out photoelectric conversion to the terminal T1 and the transistor M5 and the electric charge transmitted through M6 remain in it as it is. The transistor M3 also serves as OFF and there is no output from 2d of this pixel to a column signal line. On the other hand the transistor M5 also serves as OFF and photo-diode PD performs photoelectric conversion like drawing 3 (A) in the state where it is dissociated from others electrically and is accumulating the electric charge like drawing 3 (B). Mcccd also serves as OFF and it is in the state where an electric charge is not stored and it is in a state without an electric charge. [0075] In such the state 2d of pixels are waiting for CDS circuit 5 to end the processing which is a pixel of other lines. The one [the transistor M5 and MOS gate Mcccd(s) / all the pixels including 2d of pixels] like drawing 3 (C) all at once if signal read-out from all the pixels is completed and predetermined time passes since a photoelectric conversion start. Then the electric charge Q accumulated in photo-diode PD is simultaneously transmitted in the direction [directly under] of each MOS gate Mcccd through each transistor M5 by all the pixels. As a result the electric charge of photo-diode PD is lost and is reset.

[0076] As shown in drawing 3 (D) after an end of charge transfer the transistor M5 is set to OFF and all electric charges are transmitted directly under MOS gate Mcccd. Again photoelectric conversion of photo-diode PD is carried out and it starts accumulation of an electric charge. On the other hand Mcccd has become with one and continues holding an electric charge under a gate. 2d of pixels are in such a state and while CDS circuit 5 is processing a pixel of other lines they continue standing by.

[0077] Then if processing of 2d of pixels currently observed starts 2d of pixels will perform a reset action of the terminal T1. That is a high-level signal from a control circuit which is not illustrated is impressed to a gate electrode of the transistor M1 and makes M1 one. At this time the transistor M3 and M6 are still OFF. As a result potential of the terminal T1 serves as ($V_{dd}-V_{thrst}$). Here V_{dd} is power supply voltage and V_{thrst} is the threshold voltage of the transistor M1.

[0078] Then a signal to a gate electrode of the transistor M1 serves as a low level and is made off [M1]. Thereby the terminal T1 returns to the state where it floated electrically and a reset action completes it. Since the kTC noise ingredient V_{kTC} rides on the terminal T1 at this

time potential of the terminal T1 serves as $(V_{dd} - V_{thrst} + V_{ktc})$.

[0079] On the other hand, preparations for carrying out signal processing of 2 d of pixels even in CDS circuit 5 are made. That is, the switch S1 and S2 are closed and the terminal C2a and C1b are made into the reference potential Vref. Since M3 is considered as one by impressing a high-level signal from a control circuit which is not illustrated to a gate electrode of the transistor M3 in this state, potential of $(V_{dd} - V_{thrst} + V_{ktc} - V_{thamp})$ is outputted to multiple-message-transmission item output line i.e. terminal C2b. Here, Vthamp is the threshold voltage of the transistor M2 for amplification. As a result, potential difference of $(V_{dd} - V_{thrst} + V_{ktc} - V_{thamp} - V_{ref})$ is built over the capacitor C2.

[0080] Next, CDS circuit 5 opens the switch S2, sets it to OFF, and changes the terminal C2a (= the terminal C1b) into the state where it floated. Hereby, impressing a signal with the transistor M6 high-level from a control circuit which is not illustrated to the gate electrode as shown in drawing 3 (E), M6 is considered as one. On the other hand, if a signal of a low level is impressed to MOS gate Mcd, the electric charge Q which was directly under Mcd will be transmitted to the terminal T1 through the transistor M6. The transistor M6 after charge transfer completion is set to OFF, and as shown in drawing 3 (F), all the electric charges are transmitted to the terminal T1.

[0081] As a result, for the terminal T1, the electrical change by the electric charge Q is generated. Although the capacity Cpx1 of the terminal T1 consists of the capacity of the capacitor Cgate, capacitance Cmp of the transistor M2, and the diffusion capacitance Crst of the transistor M1 and the stray capacitance Cf of wiring, when the electric charge Q enters here, the electrical change of $\Delta V = Q / C_{px1}$ occurs. Therefore, the potential of the terminal T1 is set to $(V_{dd} - V_{thrst} + V_{ktc} + \Delta V)$.

[0082] If an electrical change happens to the terminal T1, it will be amplified by the source follower circuit with the transistor M2, and also will be outputted through the transistor M3 in an ON state to multiple-message-transmission item output line i.e. terminal C2b. Thereby, the potential of terminal C2b is set to $(V_{dd} - V_{thrst} + V_{ktc} - V_{thamp} + \Delta V)$. That is, the electrical change produced in terminal C2b is $(V_{dd} - V_{thrst} + V_{ktc} - V_{thamp} + \Delta V) - (V_{dd} - V_{thrst} + V_{ktc} - V_{thamp}) = \Delta V$. It is influenced only by the ingredient by the charge quantity Q by the photoelectric conversion of photo-diode PD, but there is also no influence of a kTC noise.

[0083] According to the electrical change of this terminal

C2bthe electrical change of proportionality part $V_{ref} + \{**V - C1/(C1+C2)\}$ with which the capacitor C1 and C2 were connected in series produces the terminal C2a (= terminal C1b) which is in the state which floated electrically. Then the switch S1 is opened it supposes that it is off and the processing result which is the above-mentioned electrical change is held to the capacitor C1. And it is supposed that the transistor M3 is off and the output from the pixel 2c is lost. [0084] Then the switch S3 is considered as one with the horizontal shift register which is not illustrated and the processing result of 2 d of pixels currently held at the capacitor C1 is outputted as a pixel signal through the switch S3. Then the switch S3 is opened again it is supposed that it is off and one cycle in 2 d of this pixel is completed. In the back the same thing is again repeated from the beginning. [0085] Explanation of operation of the above-mentioned embodiment is an example and is not limited to this. For example what is necessary is to perform reset with the transistor M1 of the terminal T1 by the above-mentioned explanation just before outputting the reset potential of the terminal T1 but just to perform it once to [somewhere in] the next signal output operation after it is not limited to this and the last signal output finishes. [0086] Since the signal and background noise which carry out a total are taken by the above operation with the reset potential performed to the same timing a kTC noise is canceled. Since the electric charge all the pixel identical time carried out [the electric charge] photoelectric conversion is outputted from a horizontal shift register one by one a field shutter function is realized. [0087] Next the 3rd embodiment and 4th embodiment of this invention are described. The representative circuit schematic of the stroke matter of a 3rd embodiment of the solid state camera with which drawing 4 becomes this invention and drawing 5 show the representative circuit schematic of the stroke matter of a 4th embodiment of the solid state camera which becomes this invention. Identical codes are given to drawing 1 drawing 2 and an identical configuration portion among both figures and the explanation is omitted. [0088] According to 1st and 2nd old embodiments reset of photo-diode PD was performed by the act of transmitting a carrier (electric charge). However in this method reset of photo-diode PD will be the exposure time which is 1 time and was always fixed to the 1 field. Since shutter speed cannot be freed now it is convenient if the transistor for photo-diode reset which became independent to photo-diode PD is attached.

[0089] So in a 3rd embodiment of this invention shown in drawing 4. The transistor M7 for photo-diode reset is formed in the pixel of a 1st embodiment and the transistor M7 for photo-diode reset is formed in the pixel of a 2nd embodiment in a 4th embodiment of this invention shown in drawing 5. That is in drawing 4 and drawing 5 the N type layer of photo-diode PD is connected to the power supply voltage Vdd via the source of MOS type field effect transistor M7 and the drain. [0090] Thereby in drawing 4 and drawing 5 if a high-level reset signal is impressed to the gate of the transistor M7 the transistor M7 is turned on and via the drain of the transistor M7 and a source the power supply voltage Vdd will be impressed to the N type layer of photo-diode PD and will reset this. That is even if the carrier of photo-diode PD does not finish being transmitted photo-diode PD is resettable to arbitrary timing by one [the transistor M7 / arbitrary timing]. Therefore in 3rd and 4th embodiments shutter time can be set up freely. [0091] In a 4th embodiment of drawing 5 since the carrier holding portion is constituted from CCD type MOS gate Mccd the potential of the portion in which the carrier directly under MOS gate Mccd is held with the potential of MOS gate Mccd can be moved freely. Thereby an advantageous operational mode can be set up.

[0092] Next other operational modes of a 4th embodiment of this invention are explained. As a method of opening a dynamic range the method of adding what has short shutter time and a long thing is known from before. It is 10msec which has long shutter time for example and short things are for example 0.5msec.

[0093] As everyone knows when shutter time is long a dark place is reflected well but a bright place will be poor white. On the other hand when shutter time is short although projection of a bright place becomes good it will be black with a dark poor place. Therefore if both information is added a dark place and a bright place can be copied together.

[0094] Hereafter operation in other modes of this 4th embodiment is concretely explained based on the composition shown in drawing 6 (A). Identical codes are given to drawing 5 and an identical configuration portion among the figure (A). The graphic display of the transistor M7M1 - M3 is omitted. First after resetting photo-diode PD photoelectric conversion between time T1 with longer shutter time is performed. then the potential of the channel of MOS gate Mccd applies the 1st potential that becomes in a potential minute half [about] when the potential of Vdd is applied to the gate electrode of Mccd to the gate electrode of Mccd.

[0095] If one [this state / the transistor M5] as shown in drawing 6 (B) a carrier (electric charge) will be transmitted under MOS gate Mccd through the transistor M5. Then the transistor M5 is made off. Thereby as shown in drawing 6 (B) the potential potential of the transistor M5 becomes high and an electric charge is held directly under MOS gate Mccd. [0096] Next, after resetting photo-diode PD again only Ts with short shutter time performs photoelectric conversion. As a black dot shows to drawing 6 (C) typically an electric charge is accumulated in photo-diode PD by this photoelectric conversion. Then the 2nd larger potential for example V_{dd} than the 1st potential is impressed to the gate electrode of MOS gate Mccd. Thereby the potential potential directly under Mccd becomes still deeper than the last state. [0097] In this state if the transistor M5 is on as shown in drawing 6 (D) the electric charge accumulated in photo-diode PD flows into MOS gate Mccd through the transistor M5 and the electric charge of this shutter time Ts is added to the electric charge at the time of the last shutter time Tl directly under Mccd. Thus if the made electric charge is outputted to Tl the signal with which the dynamic range spread can be outputted. [0098] Although NMOS FET is used in old explanation if N type and P type are replaced and the direction of voltage is made reverse of course effect same also at PMOS FET is acquired.

[0099]

[Effect of the Invention] As explained above after accumulating the electric charge acquired by carrying out photoelectric conversion simultaneously with the photo-diode of all the pixels in charge storage part such as a capacitor and a MOS gate according to this invention after facing outputting to the exterior through an output means operating the transistor for reset and an output means and sending out prescribed potential to a noise canceller. By outputting the signal corresponding to the electric charge accumulated in the charge storage part to a noise canceller through an output means having taken out only the signal component proportional to the electric charge produced by the photoelectric conversion of the photo-diode in the noise canceller A sake field shutter operation by all the pixel simultaneous photoelectric conversion and removal (kTC noise removal) of the background noise in a noise canceller can be performed simultaneously and thereby high-definition Still Picture Sub-Division can be picturized. [0100] To the electric charge which carried out photoelectric conversion with the photo-diode by the 1st

shutter time of the longer one according to this invention. Since the electric charge which carried out photoelectric conversion with the photo-diode by the 2nd shutter time of the shorter one was added directly under the MOS gate the signal with which the dynamic range spread can be outputted. [0101] Since according to this invention the voltage in inverse proportion to the capacity in the common connection terminal of the transistor for reset the 2nd transistor for charge transfer and an output means constitutes so that it may produce for this common connection terminal Since the above-mentioned capacity is small made corresponding to making area of a photo-diode small it can have composition advantageous to a miniaturization.

DESCRIPTION OF DRAWINGS

[Brief Description of the Drawings]

[Drawing 1] It is a representative circuit schematic for the stroke matter of a 1st embodiment of this invention.

[Drawing 2] It is a representative circuit schematic for the stroke matter of a 2nd embodiment of this invention.

[Drawing 3] It is a figure showing the potential of the important section of drawing 2 and the situation of movement of an electric charge.

[Drawing 4] It is a representative circuit schematic of the stroke matter of a 3rd embodiment of this invention.

[Drawing 5] It is a representative circuit schematic of the stroke matter of a 4th embodiment of this invention.

[Drawing 6] It is a figure explaining operation in other modes of a 4th embodiment of this invention.

[Drawing 7] It is a block diagram of an example of the whole solid state camera.

[Drawing 8] It is a representative circuit schematic for the stroke matter of an example of the conventional solid state camera.

[Drawing 9] It is a representative circuit schematic for the stroke matter of other examples of the conventional solid state camera.

[Drawing 10] It is a figure showing making potential of a certain capacity C into a certain potential V.

[Explanations of letters or numerals]

1 Vertical shift register

2c and 2d Pixel of a 1st and 2nd embodiment

3 Load and a noise canceller

4 Horizontal shift register

5 CDS circuit

6 Load
PD Photo-diode
M1 Field effect transistor for reset
M2 Field effect transistor for amplification (output means)
M3 Field effect transistor for an output (output means)
M5 and M6 Transistor for charge transfer (the 1st2nd
transistor for charge transfer)
M7 Field effect transistor for photo-diode reset
Mccd MOS gate
Cex Capacitor for charge storages
Ce Capacitor for capacity adjustments of a converter
S1S2and S3 Switch
T1 Terminal
